Supporting Information

High–efficiency photocatalytic reduction of Cr(VI) by Z–scheme electron transfer in UiO-66-NH₂@HDU-25 heterojunctions

Test S1. Characterizations

The morphological features of the materials surface were observed by transmission electron microscopy (TEM, JEOL F200) and scanning electron microscopy (SEM, ZEISS sigma500) and energy-dispersive spectroscopy (EDS) mapping images (EDS spectrometer attached to the TEM). The structures of the samples were examined by X-ray diffraction (XRD, SmartLab SE). X-ray photoelectron spectra (XPS) were collected on an X-ray photoelectron spectrometer (Thermo SCIENTIFIC ESCALAB Xi+). Fourier transform infrared (FT-IR) spectra of the samples were recorded using an infrared spectrometer (Shimadzu IRT racer-100). Samples were analyzed thermogravimetrically (TGA, STA 2500) over a temperature range of 25 to 800 °C with a 10 °C min⁻¹ increasing rate. The Brunauer–Emmett–Teller (BET) surface areas and pore volumes were obtained using the N_2 adsorption/desorption technique (TriStar II 3020). The UV-vis diffuse reflectance spectra (DRS, Shimadzu UV-2700) were obtained by the BaSO₄ as a reflectance standard at room temperature. The UV-vis absorption spectra are obtained by UV2355 spectrophotometer (Unico UV2355). All the photoelectrochemical tests were performed on an electrochemical workstation (Chenhua CHI E660) with a standard three-electrode system. Electron spin resonance (ESR) signals were recorded with a Bruker ESR A300 spectrometer. The zeta potential of the samples was determined by a zeta potential analyzer (Zetasizer Nano ZSE). The photocatalytic chamber (CEL-LB70) and the xenon light source system (CEL-HXF300-T3) were provided by CEAULIGHT.

In order to obtain a more reasonable structure and reduce the computational cost of the larger model, the HDU-25 structure was optimized by using the B97-3C¹ level

and SMD² implicit water solvent model by ORCA³software. In order to maintain the planar structure of the HDU-25 structure in isolation, the skeleton atoms were frozen. UiO-66-NH₂ was then extracted from the crystal structure and spliced with the optimized HDU-25 molecule. Finally, CP2K^{4,5} software was used to optimize the structure of the splice at the GFN1-Xtb⁶ level, in which only the atoms connected between UiO-66-NH₂ and HDU-25 and all the H atoms were relaxed. Based on the optimized final structure, the first 50 electronic excited singlet states were calculated at the TD-CAM-B3LYP⁷-D3(BJ)^{8,9}/def2-SVP^{10,11} calculation level. The hole-electron excited state analysis¹² and InterFragment Charge Transfer (IFCT) were performed by Multiwfn¹³ software. The cub file generated based on Multiwfn was visualized, and the image was rendered by VMD¹⁴ software.



Fig. S1. TEM images of UiO-66-NH₂@HDU-25 (0.5:1)



Fig. S2. SEM image of UiO-66-NH₂@HDU-25 (8:1)



Fig. S3. Photocatalytic effect of a series of UiO-66-NH₂@HDU-25 hybrid materials with different UiO-66-NH₂ mass contents.



Fig. S4. (a) XRD patterns, (b) FTIR spectra of a series of UiO-66-NH₂@HDU-25 hybrid materials.



Fig. S5. TG curves of a series of UiO-66-NH₂@HDU-25 hybrid materials.



Fig. S6. (a) N_2 adsorption–desorption isotherms, (b) pore size distributions of a series of UiO-66-NH₂@HDU-25 hybrid materials.



Fig. S7. Zeta potential of UiO-66-NH₂@HDU-25 at different pH values.



Fig. S8. (a-f) Pseudo-first-order kinetics curves of the photocatalytic Cr(VI) reduction reaction under different conditions.



Fig. S9. (a) Cycling performance of UiO-66-NH₂@HDU-25. (b) XRD patterns, and (c) the full XPS spectra of UiO-66-NH₂@HDU-25 before and after cycling. (d) Cr 2p spectra after cycling.



Fig. S10. (a and b) Partial structural modelling of UiO-66-NH₂@HDU-25.

Sample types	Specific surface area (m ² g ⁻¹)
UiO-66-NH ₂ @HDU-25 (0.5:1)	451
UiO-66-NH ₂ @HDU-25 (1:1)	648
UiO-66-NH ₂ @HDU-25 (2:1)	701
UiO-66-NH ₂ @HDU-25 (4:1)	722
UiO-66-NH ₂ @HDU-25 (6:1)	612
UiO-66-NH ₂ @HDU-25 (8:1)	786
UiO-66-NH ₂ @HDU-25 (10:1)	642

Table S1 Specific surface area of a series of UiO-66-NH₂@HDU-25 hybrid materials

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